

<b>Notice of References Cited</b>	Application/Control No. 10/739,351		Applicant(s)/Patent Under Reexamination TAKAHASHI ET AL.	
	Examiner Jeffrie R. Lund		Art Unit 1763	Page 1 of 3

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,780,169	10-1988	Stark et al.	156/345.34
*	B	US-4,931,135	06-1990	Horiuchi et al.	216/67
*	C	US-5,449,410	09-1995	Chang et al.	118/723ER
*	D	US-5,451,435	09-1995	Yu, Chen-Hua D.	427/585
*	E	US-5,552,017	09-1996	Jang et al.	438/710
*	F	US-5,599,513	02-1997	Masaki et al.	422/311
*	G	US-5,753,191	05-1998	Yamamoto et al.	422/143
*	H	US-5,919,332	07-1999	Koshiishi et al.	156/345.47
*	I	US-6,030,486	02-2000	Loewenhardt et al.	156/345.46
*	J	US-6,050,216	04-2000	Szapucki et al.	118/723E
*	K	US-6,113,700	09-2000	Choi, Jun-young	118/715
*	L	US-6,264,852 B1	07-2001	Herchen et al.	216/60
*	M	US-6,428,850 B1	08-2002	Shinriki et al.	427/255.32

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2000-208490 A	07-2000	JP	Ueda	--
	O	JP 2003-124192 A	04-2003	JP	Hirose et al	--
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/739,351		Applicant(s)/Patent Under Reexamination TAKAHASHI ET AL.	
	Examiner Jeffrie R. Lund		Art Unit 1763	Page 2 of 3

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,562,189 B1	05-2003	Quiles et al.	156/345.43
*	B	US-6,599,367 B1	07-2003	Nakatsuka, Sakae	118/715
*	C	US-6,733,620 B1	05-2004	Sugiyama et al.	156/345.29
*	D	US-D494,551 S	08-2004	Doba, Shigeki	D13/182
*	E	US-D496,008 S	09-2004	Takahashi et al.	D13/182
*	F	US-6,878,234 B2	04-2005	Ogasawara et al.	156/345.29
*	G	US-2003/0094135 A1	05-2003	Komiya et al.	118/715
*	H	US-2003/0209323 A1	11-2003	Yokogaki, Tsuyoshi	156/345.34
*	I	US-2004/0108066 A1	06-2004	Hayami et al.	156/345.27
*	J	US-2004/0129218 A1	07-2004	Takahashi et al.	118/715
*	K	US-2004/0244688 A1	12-2004	Himori et al.	118/723.00E
*	L	US-2004/0025788 A1	02-2004	Ogasawara et al.	118/715
*	M	US-2004/0060658 A1	04-2004	Nishimoto et al.	156/345.1

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/739,351	Applicant(s)/Patent Under Reexamination TAKAHASHI ET AL.	
	Examiner Jeffrie R. Lund	Art Unit 1763	Page 3 of 3

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0103440 A1	05-2005	Sato et al.	156/345.29
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.